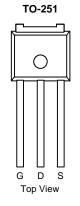
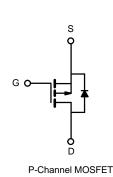


P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^d	Q _g (Typ.)			
- 30	0.018 at V _{GS} = - 10 V	- 40	13 nC			
- 30	0.022 at V _{GS} = - 4.5 V	- 35	13110			





FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET[®] Power MOSFET
- 100 % R_g Tested

Pb-free

ROHS COMPLIANT HALOGEN FREE

APPLICATIONS

- Load Switch
- · Battery Switch

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	- 30	V		
Gate-Source Voltage	V _{GS}	± 20	v		
	T _C = 25 °C		- 40		
Continuous Drain Current (T _{.I} = 150 °C)	T _C = 70 °C		- 35		
Continuous Diain Current (1) = 130 C)	T _A = 25 °C	I _D	- 30.0 ^{a, b}		
	T _A = 70 °C		- 28 ^{a, b}	A	
Pulsed Drain Current	I _{DM}	- 150			
Continuous Course Prain Diade Current	T _C = 25 °C	I-	- 3.5		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	- 2.1 ^{a, b}		
	T _C = 25 °C		40		
Maximum Dayor Dissipation	T _C = 70 °C	P _D	32	w	
Maximum Power Dissipation	T _A = 25 °C		2.5 ^{a, b}	VV	
	T _A = 70 °C		1.6 ^{a, b}		
Operating Junction and Storage Temperature Range	T _J , T _{stq}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	40	50	°C/W	
Maximum Junction-to-Foot	Steady State	R _{thJF}	24	30	- C/VV	

Notes

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under Steady State conditions is 95 °C/W.
- d. Based on $T_C = 25$ °C.



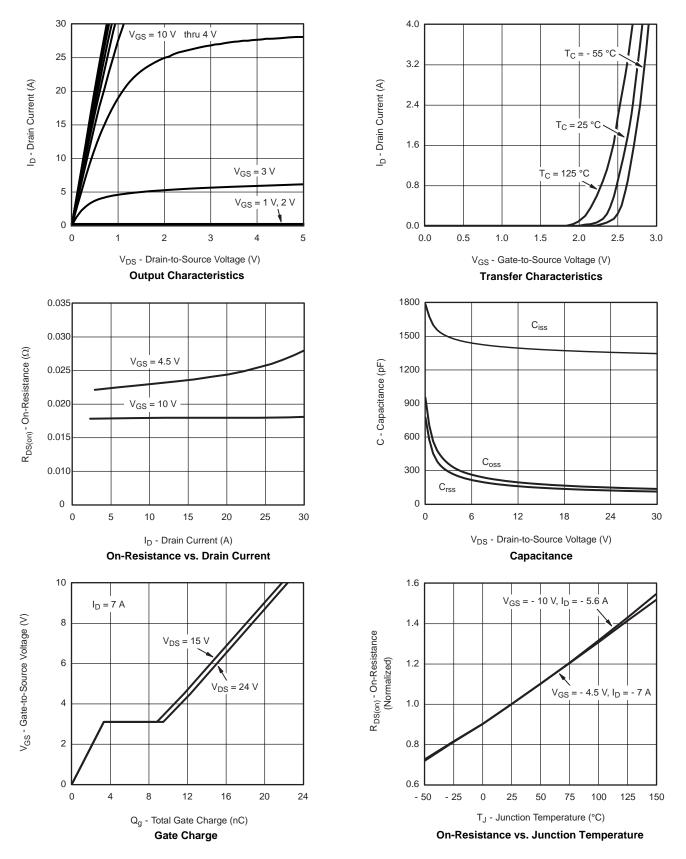
SPECIFICATIONS T _J = 25 °C, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		- 31		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			4.5		mv/·C	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1.0		- 2.5	V	
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			- 1 - 5	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 \text{ V}, V_{GS} = -10 \text{ V}$	- 20			Α	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 10 V, I _D = - 7.0 A V _{GS} = - 4.5 V, I _D = - 5.6 A		0.018 0.022		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 7.0 A		18		S	
Dynamic ^b	0.0						
Input Capacitance	C _{iss}			1455			
Output Capacitance	C _{oss}	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		180		pF	
Reverse Transfer Capacitance	C _{rss}			145			
Total Gate Charge		V _{DS} = - 15 V, V _{GS} = - 10 V, I _D = - 7.0 A		25	38	20	
	Q_g	Q_{g}		13	20		
Gate-Source Charge	Q_{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -7.0 \text{ A}$		3.5		nC	
Gate-Drain Charge	Q_{gd}			5.5		1	
Gate Resistance	R_g	f = 1 MHz	0.4	2.0	4.0	Ω	
Turn-On Delay Time	t _{d(on)}			10	20		
Rise Time	t _r	$V_{DD} = -15 \text{ V}, R_{L} = 2.7 \Omega$		13	20		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -5.6 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		23	35		
Fall Time	t _f			9	18		
Turn-On Delay Time	t _{d(on)}			38	57	ns	
Rise Time	t _r	V_{DD} = - 15 V, R_L = 2.7 Ω		89	134		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -5.6 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		22	33		
Fall Time	t _f			11	17		
Drain-Source Body Diode Characteris	stics						
Continous Source-Drain Diode Current	I_S	T _C = 25 °C			- 6.5	A	
Pulse Diode Forward Current	I _{SM}				- 30	^	
Body Diode Voltage	V_{SD}	$I_S = -5.6 \text{ A}, V_{GS} = 0 \text{ V}$		- 0.71	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			22	33	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1 - 56 A dl/dt - 100 A/vo T - 05 °C		17	26	nC	
Reverse Recovery Fall Time	t _a	$I_F = -5.6 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 °\text{C}$		13		ns	
Reverse Recovery Rise Time	t _b			9			

Notes:

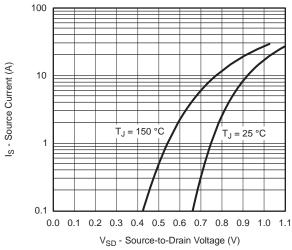
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

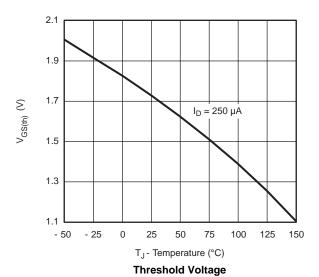






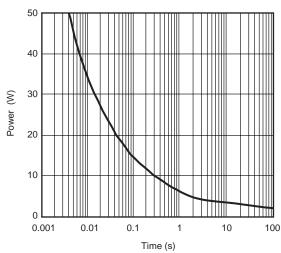


Source-Drain Diode Forward Voltage

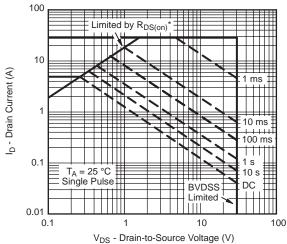


V_{GS} - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage



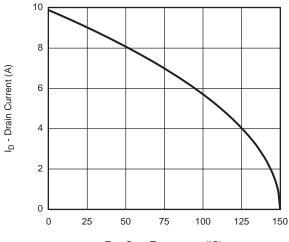
Single Pulse Power, Junction-to-Ambient



* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

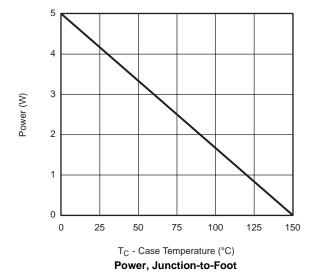
Safe Operating Area

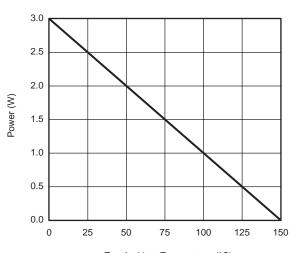




 $T_{\,C}$ - Case Temperature (°C)



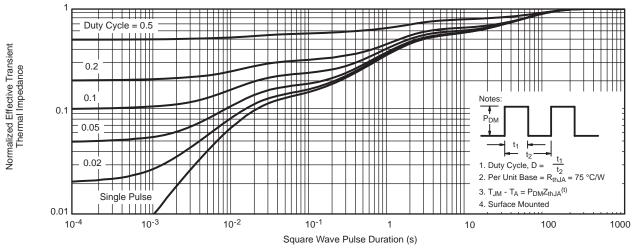




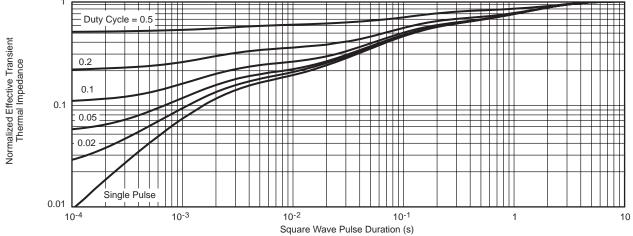
 $\label{eq:TA-Ambient Temperature (°C)}$ Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





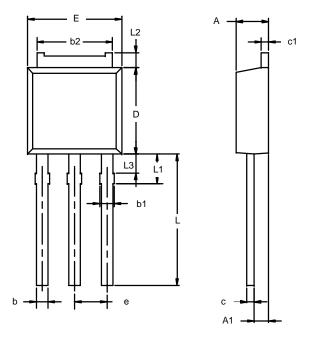
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



TO-251AA (DPAK)



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	MILLIM	IETERS	INC	HES	
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
c1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
E	6.48	6.73	0.255	0.265	
е	2.28 BSC		0.090 BSC		
L	3.89	9.53	0.153	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	
ECN: S-03946—Rev. E, 09-Jul-01 DWG: 5346					



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